# TRADEMARK ASSIGNMENT

Electronic Version v1.1
Stylesheet Version v1.1

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| SUBMISSION TYPE: | NEW ASSIGNMENT |
| NATURE OF CONVEYANCE: | Grant of Security Interest in Patents and Trademarks |

CONVEYING PARTY DATA

| Name | Formerly | Execution Date | Entity Type |
|---|---|---|---|
| JMAR Technologies, Inc. | FORMERLY f/k/a California Jamar, Inc. and f/k/a JMAR Industries, Inc. | 04/11/2007 | CORPORATION: DELAWARE |

RECEIVING PARTY DATA

| | |
|---|---|
| Name: | Laurus Master Fund, Ltd. |
| Street Address: | 335 Madison Ave., 10th Floor |
| Internal Address: | c/o Laurus Capital Management, LLC |
| City: | New York |
| State/Country: | NEW YORK |
| Postal Code: | 10017 |
| Entity Type: | COMPANY: CAYMAN ISLANDS |

PROPERTY NUMBERS Total: 2

| Property Type | Number | Word Mark |
|---|---|---|
| Registration Number: | 3027660 | BIOSENTRY |
| Serial Number: | 78670005 | VERSACAM |

CH $65.00 3027660

CORRESPONDENCE DATA

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|---|---|
| ATTORNEY DOCKET NUMBER: | CSC # 868859 |

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| NAME OF SUBMITTER: | Matthew Mayer |
| Signature: | /Matthew Mayer/ |
| Date: | 04/30/2007 |

Total Attachments: 19
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JMAR Technologies
- Trademarks

**GRANT OF SECURITY INTEREST**

**IN PATENTS AND TRADEMARKS**

THIS GRANT OF SECURITY INTEREST ("Grant"), effected as of April 11, 2007, is executed by JMAR Research, Inc. (f/k/a Jamar Technology Co. and f/k/a JMAR Technology Co., a Delaware corporation ("Research")) and JMAR Technologies, Inc. (f/k/a/ California Jamar, Inc. and f//a JMAR Industries, Inc.) ("Technologies," and together with Research, the "Grantors"), in favor of Laurus Master Fund, Ltd. (the "Secured Party").

A. Pursuant to a Security Agreement dated as of March 27, 2006 among the Grantors, certain other subsidiaries of the Grantors and the Secured Party (as amended, restated, supplemented or otherwise modified from time to time, the "Security Agreement") and a Pledge and Security Agreement dated as of March 21, 2003 among the Grantor, certain other subsidiaries of the Grantors and the Secured Party (as amended, restated, supplemented or otherwise modified from time to time, the "Pledge and Security Agreement"), the terms and provisions of which are hereby incorporated herein as if fully set forth herein, the Grantors have granted a security interest to the Secured Party in consideration of the Secured Party's agreement to provide financial accommodations to the Grantors and certain other subsidiaries of the Grantors

B. The Grantors (1) have adopted, used and are using the trademarks reflected in the trademark registrations and trademark applications in the United States Patent and Trademark Office more particularly described on Schedule 1 annexed hereto as part hereof (the "Trademarks"), and (2) have registered or applied for registration in the United States Patent and Trademark Office of the patents more particularly described on Schedule 2 annexed hereto as part hereof (the "Patents").

C. The Grantors each wish to confirm their grant to the Secured Party of a security interest in all right, title and interest of the Grantors in and to the Trademarks and Patents, and all proceeds thereof, together with the business as well as the goodwill of the business symbolized by, or related or pertaining to, the Trademarks, and the customer lists and records related to the Trademarks and Patents and all causes of action which may exist by reason of infringement of any of the Trademarks and Patents (collectively, the "T&P Collateral"), to secure the payment, performance and observance of the Obligations (as that term is defined in the Security Agreement) and the Indebtedness under, and as defined in the Pledge and Security Agreement.

NOW, THEREFORE, for good and valuable consideration, receipt of which is hereby acknowledged:

1. The Grantors each, jointly and severally, do hereby further grant to the Secured Party a security interest in the T&P Collateral to secure the full and prompt payment, performance and observance of the Obligations and the Indebtedness.

2. The Grantors each, jointly and severally, agree to perform, so long as the Security Agreement is in effect, all acts deemed necessary or desirable by the Secured Party to permit and

assist it, at the Grantors' expense, jointly and severally, in obtaining and enforcing the Trademarks and Patents in any and all countries. Such acts may include, but are not limited to, execution of documents and assistance or cooperation in legal proceedings. The Grantors hereby appoint the Secured Party as the Grantors' attorney-in-fact to execute and file any and all agreements, instruments, documents and papers as the Secured Party may determine to be necessary or desirable to evidence the Secured Party's security interest in the Trademarks and Patents or any other element of the T&P Collateral, all acts of such attorney-in-fact being hereby ratified and confirmed.

3. The Grantors each, jointly and severally, acknowledge and affirm that the rights and remedies of the Secured Party with respect to the security interest in the T&P Collateral granted hereby are more fully set forth in the Security Agreement and the rights and remedies set forth herein are without prejudice to, and are in addition to, those set forth in the Security Agreement. In the event that any provisions of this Grant are deemed to conflict with the Security Agreement, the provisions of the Security Agreement shall govern.

4. The Grantors hereby each, jointly and severally, authorize the Secured Party to file all such financing statements or other instruments to the extent required by the Uniform Commercial Code and agrees to execute all such other documents, agreements and instruments as may be required or deemed necessary by the Secured Party, in each case for purposes of affecting or continuing Secured Party's security interest in the T&P Collateral.

*[REMAINDER OF PAGE INTENTIONALLY LEFT BLANK]*

IN WITNESS WHEREOF, the Grantor has caused this instrument to be executed as of the day and year first above written.

**JMAR RESEARCH, INC.**

By: _____
Name: C. Neil Beer
Title: President

**JMAR TECHNOLOGIES, INC.**

By: _____
Name: C. Neil Beer
Title: Chief Executive Officer

LAURUS MASTER FUND, LTD.

By: _____
Name:
Title:

## SCHEDULE 1 TO GRANT OF SECURITY INTEREST

## REGISTERED TRADEMARKS AND TRADEMARK APPLICATIONS

| Trademark | Registration or Application Number | Registration or Application Date | Country |
|---|---|---|---|
| Versacam | 78670005 | 7/13/05 | US |
| Biosentry | 3027660 | 12/13/06 | US |
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Note: The Biosentry application was filed by JMAR on behalf of Gregory Quist and David Drake who were the original owners of this trademark. JMAR subsequently acquired their Biosentry technology and received an assignment of this application (which ultimately was registered). The Assignment has been recorded in the US PTO.

## SCHEDULE 2 TO GRANT OF SECURITY INTEREST

### PATENTS AND PATENT APPLICATIONS

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Laser Plasma X-Ray Source | US | 1/19/1990 | 07/467,779 | 3/26/1991 | 5,003,543 |
| Laser Plasma X-Ray Source | US | 12/13/1990 | 07/627,210 | 2/18/1992 | 5,089,711 |
| Low Cost, High Average Power High Brightness Solid State Laser | US | 8/24/1994 | 08/295,283 | 7/18/1995 | 5,434,875 |
| Low Cost, High Average Power High Brightness Solid State Laser | US | 11/15/1994 | 08/339,755 | 2/13/1996 | 5,491,707 |
| Laser Generated X-ray Source | US | 5/4/1994 | 08/434,860 | 7/23/1996 | 5,539,764 |
| X-ray Target Tape System | US | 1/16/1996 | 08/585,695 | 9/16/1997 | 5,668,848 |
| Portable Laser for Blood Sampling | US | 12/23/1994 | 08/363,751 | | |
| Low Cost, High Average Brightness Solid State Laser | US | 4/27/1995 | 08/429,589 | | |
| Low Cost, High Average Power, High Brightness Solid State Laser | US | 7/17/1995 | 08/503,373 | | |
| Portable Laser for Blood Sampling | US | 9/18/1995 | 08/529,526 | 9/7/1999 | 5,947,957 |
| Pocket-Size Laser Knife | US | 11/6/1995 | 08/554,561 | | |
| Pocket-Size, Continuous-Wave Laser Knife | US | 3/20/1996 | 08/618,990 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Solid-State Laser System for Ultra-Violet Micro-Lithography | US | 6/13/1996 | 08/663,476 | | |
| Device and Method for Making Very Shallow Surface Cuts | US | 10/4/1996 | 08/725,749 | | |
| Picosecond Laser | US | 10/4/1996 | 08/725,750 | 4/21/1998 | 5,742,634 |
| Solid-State Laser System for Ultra-Violet Micro-Lithography | US | 11/22/1996 | 08/755,166 | 8/17/1999 | 5,940,418 |
| Low Cost, High Average Power, High Brightness Solid State Laser | US | 4/21/1997 | 08/845,185 | 8/4/1998 | 5,790,574 |
| Solid-State Laser System for Ultra-Violet Micro-Lithography | PCT | 6/11/1997 | PCT/US97/11693 | | |
| Picosecond Laser | PCT | 10/3/1997 | PCT/US97/18009 | | |
| Low Cost, High Average Power, High Brightness Solid State Laser | PCT | 11/6/1995 | PCT/US95/14258 | | |
| Low Cost, High Average Power, High Brightness Solid State Laser | EPC | 11/6/1995 | 95944024.9 | 0792530 | 1/21/2004 |
| Low Cost, High Average Power, High Brightness Solid State Laser | DE | 11/6/1995 | 95944024.9 | 0792530 | 1/21/2004 |
| Low Cost, High Average Power, High Brightness Solid State Laser | FR | 11/6/1995 | 95944024.9 | 0792530 | 1/21/2004 |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Low Cost, High Average Power, High Brightness Solid State Laser | GB | 11/6/1995 | 95944024.9 | 0792530 | 2/21/2004 |
| Low Cost, High Average Power, High Brightness Solid State Laser | NL | 11/6/1995 | 95944024.9 | 0792530 | 2/21/2004 |
| Low Cost, High Average Power, High Brightness Solid State Laser | JP | 5/15/1997 | 08-516895 | | |
| Low Cost, High Average Power, High Brightness Solid State Laser | KR | 5/15/1997 | 97-703260 | 1/22/2003 | 0371125 |
| Low Cost, High Average Power, High Brightness Solid State Laser | SG | 11/6/1995 | 9702157-0 | 1/18/1999 | 41076 |
| Solid-State Laser System for Ultra-Violet Micro-Lithography | PCT | 11/21/1997 | PCT/US97/21786 | | |
| Short Pulse Laser System | US | 4/9/1998 | 09/058,274 | 1/18/2000 | 6,016,324 |
| Laser Plasma X-Ray Source | JP | 12/20/1990 | | | |
| Laser Plasma X-Ray Source | PCT | 12/20/1990 | PCT/US90/07557 | | |
| Device and Method to Manage Thermal Effects in Laser Crystals and Dielectric | US | 8/5/1998 | 60/095,375<br>Provisional | | |
| Device and Method to Manage Thermal Effects in Laser Crystals and Dielectric | US | 8/5/1999 | 09/368,896 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Shaped Field Soft X-Ray, Extreme Ultraviolet and Ultraviolet Source | US | 10/27/1998 | 60/105,861<br>Provisional | | |
| Shaped Field Soft X-Ray, Extreme Ultraviolet and Ultraviolet Source | US | 10/27/1998 | 09/429,738 | 10/23/2001 | 6,307,913 |
| Beam Correcting Laser Amplifier | US | 10/15/1999 | 60/159,521<br>Provisional | | |
| Beam Correcting Laser Amplifier | US | 10/12/2000 | 09/689,539 | | |
| Method and Apparatus for Laser Ablation of a Target Material | US | 3/27/1999 | 09/385,539 | 10/29/2002 | 6,472,295 |
| Short Pulse Laser System | EPC | 4/1/1999 | 99302609.5 | | |
| Short Pulse Laser System | JP | 4/9/1999 | 11-103255 | | |
| Short Pulse Laser System | KR | 4/28/1999 | 99-11833 | | |
| Short Pulse Laser System | SG | 4/6/1999 | 9901635-4 | 9/18/2001 | 75166 |
| Pico Second Laser | EPC | 10/3/1997 | 97954889.8 | | |
| Pico Second Laser | JP | 4/5/1999 | 10-518703 | | |
| Pico Second Laser | KR | 4/6/1999 | 10-1999-7002961 | 5/21/2002 | 339057 |
| Pico Second Laser | SG | 10/3/1997 | 9901472-2 | 1/16/2001 | 64716 |
| Parallel X-Ray Nanotomography | US | 5/24/1999 | 60/135,639<br>Provisional | | |
| Parallel X-Ray Nanotomography | US | 5/24/2000 | 09/578,115 | 5/14/2002 | 6,389,101 |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Optical Apparatus and Method for Inspecting Polished and Unpolished Substrates | US | | | | |
| Laser Plasma X-Ray Generating System and Method Using Solid Micro-Micropellet | US | 10/27/1999 | 60/161,891<br>Provisional | | |
| High Collection Angle Short Wavelength Radiation Collimator and Focusing Optic | US | 7/21/1999 | 60/145,489<br>Provisional | | |
| High Collection Angle Short Wavelength Radiation Collimator and Focusing Optic | US | 7/21/2000 | 09/621,404 | 9/23/2003 | 6,624,431 |
| Shaped Field Soft X-Ray, Extreme Ultraviolet and Ultraviolet Source | PCT | 10/27/1999 | PCT/US99/25271 | | |
| X-Ray Source and Method of Using Same | US | 3/1/2000 | 09/516,062 | | |
| Parallel X-Ray Nanotomography | PCT | 5/24/2000 | PCT/US00/14320 | | |
| Collimator and Focusing Optic | US | 6/5/2000 | 60/209,438<br>Provisional | | |
| Collimator and Focusing Optic | US | 7/21/2000 | 09/621,027 | | |
| High Collection Angle Short Wavelength Radiation Collimator and Focusing Optic | PCT | 7/21/2000 | PCT/US00/40447 | | |
| Collimator and Focusing Optic | PCT | 7/21/2000 | PCT/US00/40443 | | |
| Method and Apparatus for Laser Ablation of a Target Material | PCT | 8/25/2000 | PCT/US00/23362 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Radiation Generating System Using Microtargets and Method for Using Same | US | 10/27/2000 | 09/699,142 | | |
| Beam Correcting Laser Amplifier | PCT | 10/27/2000 | PCT/US00/28252 | | |
| Radiation Generating System Using Microtargets and Method for Using Same | PCT | 10/27/2000 | PCT/US00/29743 | | |
| System and Method for Providing a Pulse Laser | US | 5/8/2002 | 60/378,847<br>Provisional | | |
| Liquid Droplet Laser Plasma X-Ray Point Source and Apparatus | US | | | | |
| High Intensity and High Power Solid State Laser Amplifying System and Method | US | 7/16/2001 | 09/907,154 | 2/14/06 | 6,999,491 |
| Radiation Generating System Using Microtargets and Method for Using Same | EP | 10/27/2000 | 00973974.9 | | |
| Radiation Generating System Using Microtargets and Method for Using Same | JP | 10/27/2000 | 2001-534180 | | |
| Parallel X-Ray Nanotomography | EPC | 11/30/2001 | 00937736.7 | | |
| Collimator and Focusing Optic | JP | 7/21/2000 | 2001-512975 | | |
| Collimator and Focusing Optic | EPC | 3/7/2002 | 00960174.1 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Method and Apparatus for Laser Ablation of a Target Material | EPC | 8/25/2000 | 00959403.7 | | |
| Beam Correcting Laser Amplifier | EPC | 10/12/2000 | 00972112.7 | | |
| Beam Correcting Laser Amplifier | JP | 10/12/2000 | 2001-531185 | | |
| Method and Apparatus for Laser Ablation of a Target Material | US | 10/3/2002 | 10/264,248 | 4/6/2004 | 6,717,101 |
| High Intensity and High Power Solid State Laser Amplifying System and Method | PCT | 7/16/2002 | PCT/US02/22597 | | |
| Method and Apparatus for Generating a Membrane Target for Laser Produced Plasma | US | 1/2/2003 | 60/437,647<br>Provisional | | |
| High Power Diode-Pumped Solid State Laser and Method of Manufacturing Same | US | 4/3/2003 | 60/460,315<br>Provisional | | |
| Method and System for Providing a Pulse Laser | US | 5/8/2003 | 10/434,017 | 2/28/06 | 7,006,540 |
| Method and System for Providing a Pulse Laser | PCT | 5/8/2003 | PCT/US03/14269 | | |
| Improved Debris Mitigation Apparatus for Microtarget EUV Source | US | 7/9/2003 | 60/485,843<br>Provisional | | |
| Method And Apparatus For Generating A Membrane Target For Laser Produced Plasma | PCT | 12/31/2003 | PCT/US03/41694 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Method And Apparatus For Generating A Membrane Target For Laser Produced Plasma | US | 12/31/2003 | 10/750,022 | 12/20/05 | 6,977,383 |
| Single Pass Cu Ribbon Target | US | 12/17/2003 | 60/530,335 Provisional | | |
| All-Polycapillary Hybrid X-Ray Collimator With Virtual S-Bend | US | 1/9/2004 | 60/535,334 Provisional | | |
| Missile Defense Using Laser Induced Atmospheric Ionization For Virtual Direct Energy Injection | US | 1/9/2004 | 60/535,307 Provisional | | |
| High Intensity and High Power Solid State Laser Amplifying System and Method | JP | 7/16/2002 | 2003-513305 | | |
| High Intensity and High Power Solid State Laser Amplifying System and Method | EP | 7/16/2002 | 02752378.6 | | |
| Scalable DPSS Laser and Contained Target Generator | US | 2/20/2004 | 60/546,353 Provisional | | |
| Diode-Pumped Solid State Laser System Utilizing High Power Diode Bars | US | 4/2/2004 | 10/816,728 | | |
| Diode-Pumped Solid State Laser System Utilizing High Power Diode Bars | PCT | 4/2/2004 | PCT/US04/10322 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Nanometer Surface Ablation for Micro-Plasma Spectrometry | US | 3/29/2004 | 60/557,364<br>Provisional | | |
| Morphology And Spectroscopy Of Nanoscale Regions Using X-Rays Generated By Laser Produced Plasma | US | 3/29/2005 | 10/907,321 | | |
| Razor Array Shutter for LPP Debris Mitigation | US | 7/27/2004 | 60/591,410<br>Provisional | | |
| Radiation-Resistant Zone Plates | US | 8/5/2004 | 60/598,966<br>Provisional | | |
| Condenser Zone Plate Illumination for Point X-Ray Sources | US | 8/5/2004 | 60/599,203<br>Provisional | | |
| Improvement in Resolution by Using Illumination Incident at an Angle | US | 9/17/2004 | 60/611,185<br>Provisional | | |
| Method and System for Achieving Eucentric Alignment of an Object | US | 8/19/2004 | 60/602,742<br>Provisional | | |
| Systems and Methods for Tape Advancement in Laser Produced Plasma Equipment | US | 12/16/2004 | 11/014,303 | | |
| Microgripper Capillary Holder for XRM Vibration Mitigation | US | 10/18/2004 | 60/619,892<br>Provisional | | |
| Glass Capillary Stabilization for XRM Vibration Mitigation | US | 11/11/2004 | 60/626,905<br>Provisional | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Novel Soft X-Ray Source by Laser-Produced Plasma (LPP) of a Nylon Target | US | 1/7/2005 | 60/642,293 Provisional | | |
| Multi-Directional Scanning Boom Microscope | US | 1/21/2005 | 60/645,647 Provisional | | |
| Method and System for Providing a Pulse Laser | EP | 11/8/2004 | 03726679.8 | | |
| Method and System for Providing a Pulse Laser | JP | 11/8/2004 | 2004-504355 | | |
| Method and System for Providing a Pulse Laser | KR | 11/8/2004 | 10-2004-7018021 | | |
| Morphology And Spectroscopy Of Nanoscale Regions Using X-Rays Generated By Laser Produced Plasma | PCT | 3/29/2005 | PCT/US05/ 10406 | | |
| Cylindrical Optic for Particle Identification System in Fluids | US | 5/6/2005 | 60/678,354 Provisional | | |
| Multi-Angle Light Scattering Particle Identification System | US | 6/13/2005 | 60/690,535 Provisional | | |
| Improved Zone Plates for High Order Focusing Mode for X-Ray Nanoplasma | US | 6/13/2005 | 60/690,329 Provisional | | |
| High Intensity and High Power Solid State Laser Amplifying System and Method | US | 7/25/2005 | 11/188,398 | | |
| Laser Produced X-Ray Source Size Characterization | US | 7/19/2005 | 60/700,593 Provisional | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Rotating Shutter for Laser-Produced Plasma Debris Mitigation | US | 7/27/2005 | 11/161,237 | | |
| Depth Of Field And Chromatic Aberration Correction For X-Ray Wavelength Fresnel Zone Plates | US | 7/22/2005 | 60/701,842<br>Provisional | | |
| Radiation Resistant Zone Plate | US | 8/5/2005 | 11/161,510 | | |
| Condenser Zone Plate Illumination for Point X-Ray Sources | US | 8/5/2005 | 11/161,509 | | |
| Objective Zone Plate with Central Obscuration for Enhanced Depth of Field in X-Ray Microscopy | US | 8/19/2004 | 60/602,696<br>Provisional | | |
| Method and App. for Enhanced Depth of Field in X-Ray Microscopy Using Objective Zone Plate Obscuration | US | 8/19/2005 | 11/161,880 | | |
| Rotatable Glass Microcapillary Sample Holder for Tomography | US | 2/25/2005 | 60/656,724<br>Provisional | | |
| High Capture Angle MALS Instrument for Liquid Suspensions of Microorganisms | US | 5/2/2005 | 60/676,730<br>Provisional | | |
| Method and Apparatus for Nanoscale Surface Analysis Using Soft X-Rays | US | 12/14/2005 | 11/300,552 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Systems and Method for Determining Molecular Weights and Sizes Using Multi-Angle Light Scattering | US | 10/20/2005 | 60/728,678<br>Provisional | | |
| Systems and Methods for Detecting Scattered Light from a Particle Using Illumination Incident at an Angle | US | 09/19/2005 | 11/231,350 | | |
| Systems and Methods for Detecting Scattered Light from a Particle Using Illumination Incident at an Angle | PCT | 09/19/2005 | PCT/US2005/033368 | | |
| Multiple Agile Laser Source for Real Time Spark Spectrochemical Hazard in the Field | US | 10/11/05 | 60/725,455<br>Provisional | | |
| Systems and Methods for a Scanning Boom Microscope | US | 1/20/06 | 11/336,390 | | |
| Systems and Methods for a Scanning Boom Microscope | PCT | 1/20/06 | PCT/US2006/02135 | | |
| Britelight Laser Master Oscillator Pockel Cell Trigger Method and Circuit | US | 2/6/06 | 60/765,522<br>Provisional | | |
| Orthogonal Spectroscopic Technology for the Detection of Hazardous Substances | US | 3/20/06 | 60/783,975<br>Provisional | | |
| Systems and Methods for a High Capture Angle, Multiple Angle Light Scattering (MALS) Instrument | US | 5/2/06 | 11/381,346 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Systems and Methods for a High Capture Angle, Multiple Angle Light Scattering (MALS) Instrument | PCT | 5/2/06 | PCT/US2006/16950 | | |
| Systems and Methods for a Multiple Angle Light Scattering (MALS) Instrument Having Two-Dimensional Detector Array | US | 6/13/06 | 11/453,278 | | |
| Systems and Methods for a Multiple Angle Light Scattering (MALS) Instrument Having Two-Dimensional Detector Array | PCT | 6/13/06 | PCT/US2006/23043 | | |
| Systems and Methods for Achieving a Required Spot Says for Nanoscale Surface Analysis Using Soft X-Rays | US | 6/13/06 | 11/453,338 | | |
| Systems and Methods for Achieving a Required Spot Says for Nanoscale Surface Analysis Using Soft X-Rays | PCT | 6/13/06 | PCT/US06/23138 | | |
| Hybrid X-Ray and Visible Wavelength Zone Plate for Easy X-Ray Optic Alignment | US | 6/20/06 | 60/805,290<br>Provisional | | |
| Method, Apparatus, and System for Extending Depth of Field (DOF) in A Short-Wavelength Microscope Using Wavefront Encoding | US | 7/24/06 | 11/459,605 | | |

| Title | Ctry | Filing Date | Serial No. | Issue Date | Patent No. |
|---|---|---|---|---|---|
| Integrated Visible Light Microscope and Full Field Imaging Soft X-Ray Microscope | US | 8/18/2006 | 60/822,869<br>Provisional | | |
| Cryogenic XRMSample System | US | 8/18/2006 | 60/822,865<br>Provisional | | |
| Glitch Suppression Circuit and Method | US | 7/26/2001 | 09/915,745 | 1/13/2004 | 6,678,759 |